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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.








Details

Product Status	Obsolete
Number of LABs/CLBs	4548
Number of Logic Elements/Cells	90960
Total RAM Bits	4520488
Number of I/O	534
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	780-BBGA
Supplier Device Package	780-FBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2s90f780c4

Timing Model	5-20
Preliminary & Final Timing	5-20
I/O Timing Measurement Methodology	5-21
Performance	5-27
Internal Timing Parameters	5-34
Stratix II Clock Timing Parameters	5-41
Clock Network Skew Adders	5-50
IOE Programmable Delay	5-51
Default Capacitive Loading of Different I/O Standards	5-52
I/O Delays	5-54
Maximum Input & Output Clock Toggle Rate	5-66
Duty Cycle Distortion	5-77
DCD Measurement Techniques	5-78
High-Speed I/O Specifications	5-87
PLL Timing Specifications	5-91
External Memory Interface Specifications	5-94
JTAG Timing Specifications	5-96
Document Revision History	5-97

Chapter 6. Reference & Ordering Information

Software	6-1
Device Pin-Outs	6-1
Ordering Information	6-1
Document Revision History	6-2

Visual Cue	Meaning
<i>Italic type</i>	Internal timing parameters and variables are shown in italic type. Examples: t_{PIA} , $n + 1$. Variable names are enclosed in angle brackets (< >) and shown in italic type. Example: <file name>, <project name>.pdf file.
Initial Capital Letters	Keyboard keys and menu names are shown with initial capital letters. Examples: Delete key, the Options menu.
“Subheading Title”	References to sections within a document and titles of on-line help topics are shown in quotation marks. Example: “Typographic Conventions.”
Courier type	Signal and port names are shown in lowercase Courier type. Examples: data1, tdi, input. Active-low signals are denoted by suffix n, e.g., resetn. Anything that must be typed exactly as it appears is shown in Courier type. For example: c:\qdesigns\tutorial\chiptrip.gdf. Also, sections of an actual file, such as a Report File, references to parts of files (e.g., the AHDL keyword SUBDESIGN), as well as logic function names (e.g., TRI) are shown in Courier.
1., 2., 3., and a., b., c., etc.	Numbered steps are used in a list of items when the sequence of the items is important, such as the steps listed in a procedure.
	Bullets are used in a list of items when the sequence of the items is not important.
	The checkmark indicates a procedure that consists of one step only.
	The hand points to information that requires special attention.
	The caution indicates required information that needs special consideration and understanding and should be read prior to starting or continuing with the procedure or process.
	The warning indicates information that should be read prior to starting or continuing the procedure or processes
	The angled arrow indicates you should press the Enter key.
	The feet direct you to more information on a particular topic.

Document Revision History

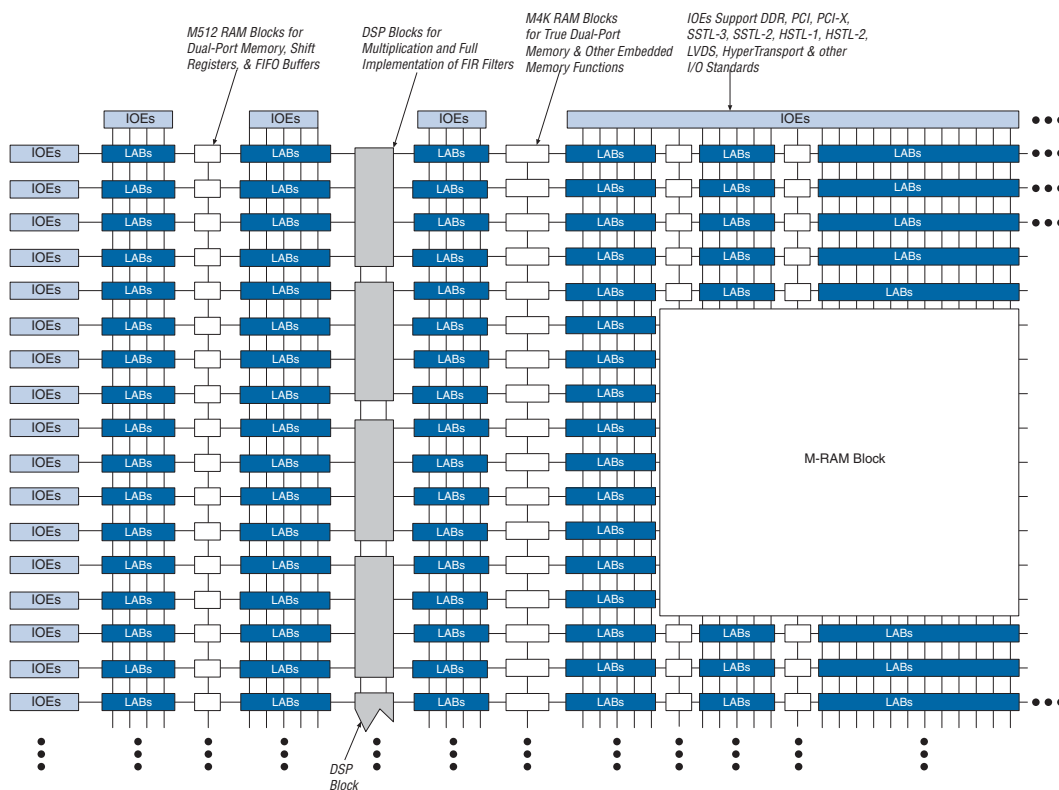
Table 1–6 shows the revision history for this chapter.

Table 1–6. Document Revision History		
Date and Document Version	Changes Made	Summary of Changes
May 2007, v4.2	Moved Document Revision History to the end of the chapter.	—
April 2006, v4.1	<ul style="list-style-type: none"> • Updated “Features” section. • Removed Note 4 from Table 1–2. • Updated Table 1–4. 	—
December 2005, v4.0	<ul style="list-style-type: none"> • Updated Tables 1–2, 1–4, and 1–5. • Updated Figure 2–43. 	—
July 2005, v3.1	<ul style="list-style-type: none"> • Added vertical migration information, including Table 1–4. • Updated Table 1–5. 	—
May 2005, v3.0	<ul style="list-style-type: none"> • Updated “Features” section. • Updated Table 1–2. 	—
March 2005, v2.1	Updated “Introduction” and “Features” sections.	—
January 2005, v2.0	Added note to Table 1–2.	—
October 2004, v1.2	Updated Tables 1–2, 1–3, and 1–5.	—
July 2004, v1.1	<ul style="list-style-type: none"> • Updated Tables 1–1 and 1–2. • Updated “Features” section. 	—
February 2004, v1.0	Added document to the Stratix II Device Handbook.	—

Each Stratix II device I/O pin is fed by an I/O element (IOE) located at the end of LAB rows and columns around the periphery of the device. I/O pins support numerous single-ended and differential I/O standards. Each IOE contains a bidirectional I/O buffer and six registers for registering input, output, and output-enable signals. When used with dedicated clocks, these registers provide exceptional performance and interface support with external memory devices such as DDR and DDR2 SDRAM, RLD RAM II, and QDR II SRAM devices. High-speed serial interface channels with dynamic phase alignment (DPA) support data transfer at up to 1 Gbps using LVDS or HyperTransport™ technology I/O standards.

Figure 2-1 shows an overview of the Stratix II device.

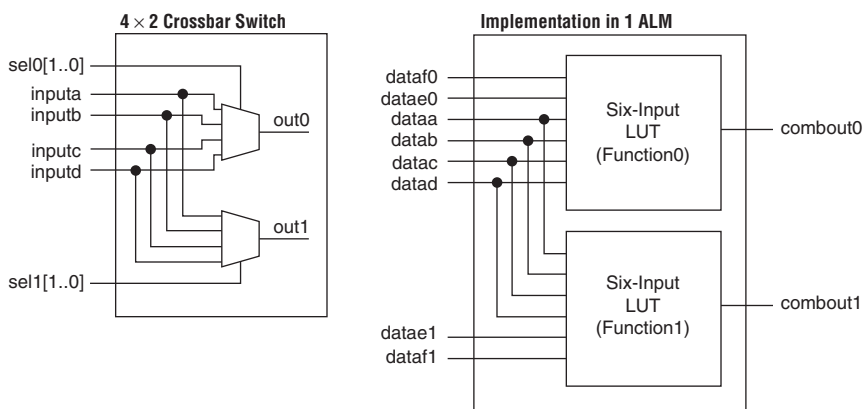
Figure 2-1. Stratix II Block Diagram



For the packing of two five-input functions into one ALM, the functions must have at least two common inputs. The common inputs are `dataaa` and `datadb`. The combination of a four-input function with a five-input function requires one common input (either `dataaa` or `datadb`).

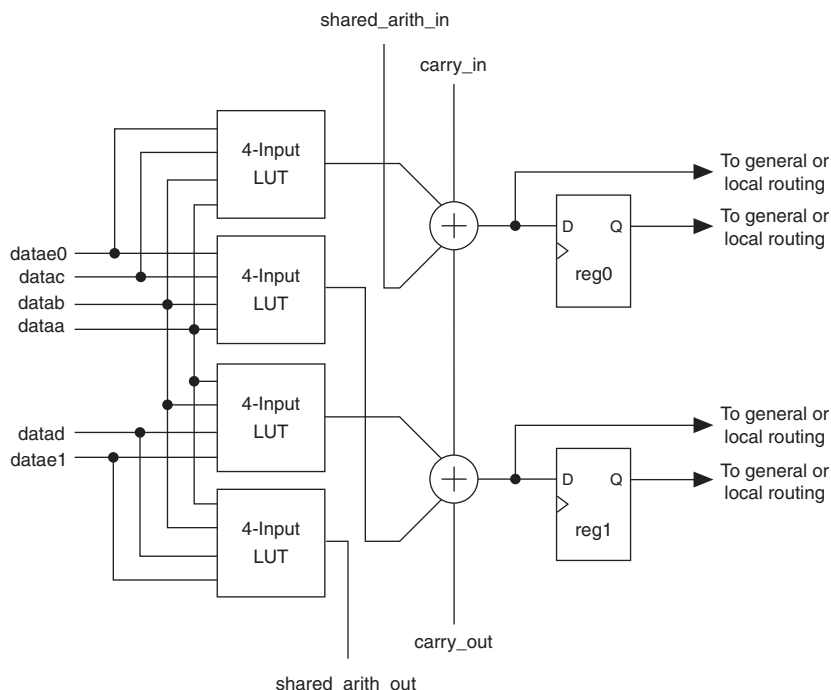
In the case of implementing two six-input functions in one ALM, four inputs must be shared and the combinational function must be the same. For example, a 4×2 crossbar switch (two 4-to-1 multiplexers with common inputs and unique select lines) can be implemented in one ALM, as shown in [Figure 2–8](#). The shared inputs are `dataaa`, `datadb`, `dataac`, and `datad`, while the unique select lines are `datae0` and `dataf0` for `function0`, and `datae1` and `dataf1` for `function1`. This crossbar switch consumes four LUTs in a four-input LUT-based architecture.

Figure 2–8. 4×2 Crossbar Switch Example



In a sparsely used device, functions that could be placed into one ALM may be implemented in separate ALMs. The Quartus II Compiler spreads a design out to achieve the best possible performance. As a device begins to fill up, the Quartus II software automatically utilizes the full potential of the Stratix II ALM. The Quartus II Compiler automatically searches for functions of common inputs or completely independent functions to be placed into one ALM and to make efficient use of the device resources. In addition, you can manually control resource usage by setting location assignments.

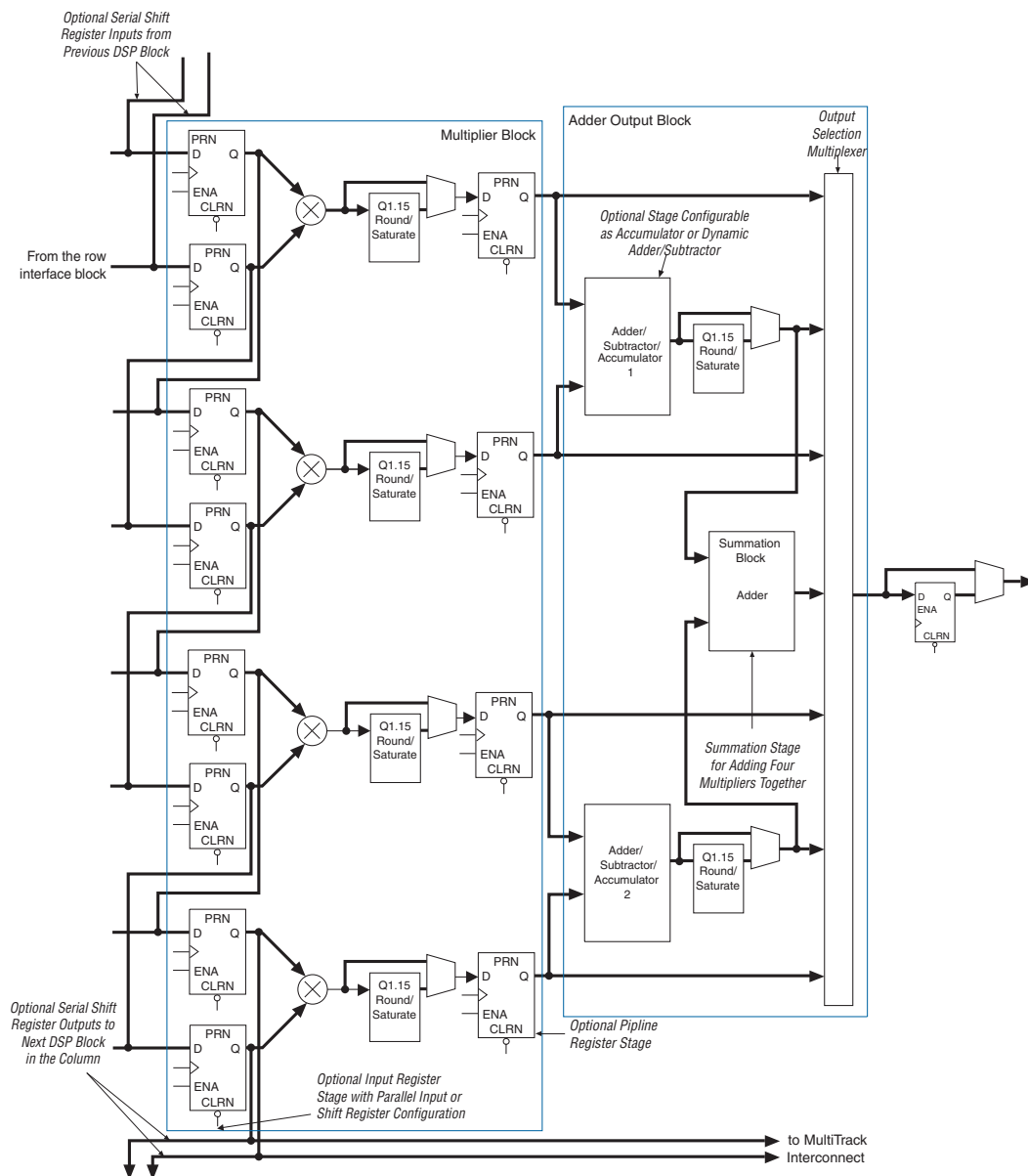
Any six-input function can be implemented utilizing inputs `dataaa`, `datadb`, `dataac`, `datad`, and either `datae0` and `dataf0` or `datae1` and `dataf1`. If `datae0` and `dataf0` are utilized, the output is driven to `register0`, and/or `register0` is bypassed and the data drives out to the interconnect using the top set of output drivers (see [Figure 2–9](#)). If

Figure 2–13. ALM in Shared Arithmetic Mode**Note to Figure 2–13:**

- (1) Inputs dataae0 and datae1 are available for register packing in shared arithmetic mode.

Adder trees can be found in many different applications. For example, the summation of the partial products in a logic-based multiplier can be implemented in a tree structure. Another example is a correlator function that can use a large adder tree to sum filtered data samples in a given time frame to recover or to de-spread data which was transmitted utilizing spread spectrum technology.

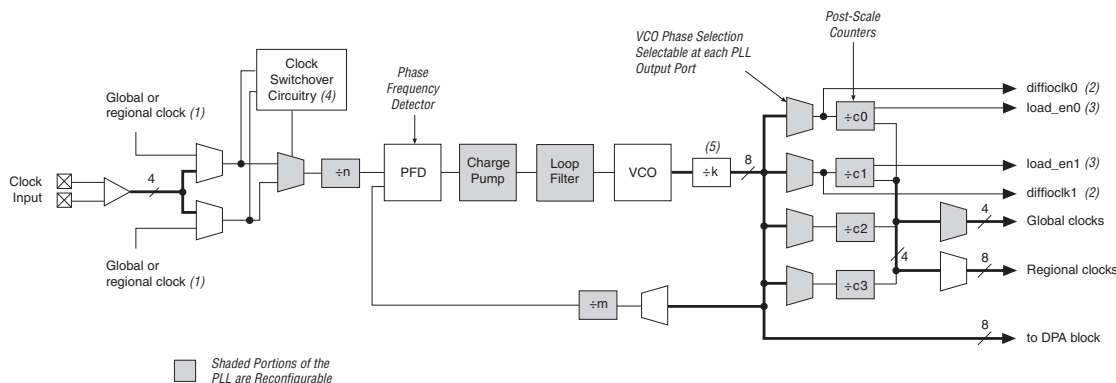
An example of a three-bit add operation utilizing the shared arithmetic mode is shown in Figure 2–14. The partial sum ($S[2..0]$) and the partial carry ($C[2..0]$) is obtained using the LUTs, while the result ($R[2..0]$) is computed using the dedicated adders.

Figure 2–28. DSP Block Diagram for 18 × 18-Bit Configuration

Fast PLLs

Stratix II devices contain up to eight fast PLLs with high-speed serial interfacing ability. Figure 2–45 shows a diagram of the fast PLL.

Figure 2–45. Stratix II Device Fast PLL Notes (1), (2), (3)



Notes to Figure 2–45:

- (1) The global or regional clock input can be driven by an output from another PLL, a pin-driven dedicated global or regional clock, or through a clock control block, provided the clock control block is fed by an output from another PLL or a pin-driven dedicated global or regional clock. An internally generated global signal cannot drive the PLL.
- (2) In high-speed differential I/O support mode, this high-speed PLL clock feeds the SERDES circuitry. Stratix II devices only support one rate of data transfer per fast PLL in high-speed differential I/O support mode.
- (3) This signal is a differential I/O SERDES control signal.
- (4) Stratix II fast PLLs only support manual clock switchover.
- (5) If the design enables this $\div 2$ counter, then the device can use a VCO frequency range of 150 to 520 MHz.



See the *PLLs in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II Device Handbook* or the *Stratix II GX Device Handbook* for more information on enhanced and fast PLLs. See [“High-Speed Differential I/O with DPA Support” on page 2–96](#) for more information on high-speed differential I/O support.

I/O Structure

The Stratix II IOEs provide many features, including:

- Dedicated differential and single-ended I/O buffers
- 3.3-V, 64-bit, 66-MHz PCI compliance
- 3.3-V, 64-bit, 133-MHz PCI-X 1.0 compliance
- Joint Test Action Group (JTAG) boundary-scan test (BST) support
- On-chip driver series termination
- On-chip parallel termination
- On-chip termination for differential standards
- Programmable pull-up during configuration

Table 2–14. DQS & DQ Bus Mode Support (Part 2 of 2) *Note (1)*

Device	Package	Number of ×4 Groups	Number of ×8/×9 Groups	Number of ×16/×18 Groups	Number of ×32/×36 Groups
EP2S90	484-pin Hybrid FineLine BGA	8	4	0	0
	780-pin FineLine BGA	18	8	4	0
	1,020-pin FineLine BGA	36	18	8	4
	1,508-pin FineLine BGA	36	18	8	4
EP2S130	780-pin FineLine BGA	18	8	4	0
	1,020-pin FineLine BGA	36	18	8	4
	1,508-pin FineLine BGA	36	18	8	4
EP2S180	1,020-pin FineLine BGA	36	18	8	4
	1,508-pin FineLine BGA	36	18	8	4

Notes to Table 2–14:

- (1) Check the pin table for each DQS/DQ group in the different modes.

A compensated delay element on each DQS pin automatically aligns input DQS synchronization signals with the data window of their corresponding DQ data signals. The DQS signals drive a local DQS bus in the top and bottom I/O banks. This DQS bus is an additional resource to the I/O clocks and is used to clock DQ input registers with the DQS signal.

The Stratix II device has two phase-shifting reference circuits, one on the top and one on the bottom of the device. The circuit on the top controls the compensated delay elements for all DQS pins on the top. The circuit on the bottom controls the compensated delay elements for all DQS pins on the bottom.

Each phase-shifting reference circuit is driven by a system reference clock, which must have the same frequency as the DQS signal. Clock pins CLK[15 . . 12] p feed the phase circuitry on the top of the device and clock pins CLK[7 . . 4] p feed the phase circuitry on the bottom of the device. In addition, PLL clock outputs can also feed the phase-shifting reference circuits.

Figure 2–56 illustrates the phase-shift reference circuit control of each DQS delay shift on the top of the device. This same circuit is duplicated on the bottom of the device.

The bus-hold circuitry also pulls undriven pins away from the input threshold voltage where noise can cause unintended high-frequency switching. You can select this feature individually for each I/O pin. The bus-hold output drives no higher than V_{CCIO} to prevent overdriving signals. If the bus-hold feature is enabled, the programmable pull-up option cannot be used. Disable the bus-hold feature when the I/O pin has been configured for differential signals.

The bus-hold circuitry uses a resistor with a nominal resistance (R_{BH}) of approximately 7 k Ω to weakly pull the signal level to the last-driven state. See the *DC & Switching Characteristics* chapter in the *Stratix II Device Handbook, Volume 1*, for the specific sustaining current driven through this resistor and overdrive current used to identify the next-driven input level. This information is provided for each V_{CCIO} voltage level.

The bus-hold circuitry is active only after configuration. When going into user mode, the bus-hold circuit captures the value on the pin present at the end of configuration.

Programmable Pull-Up Resistor

Each Stratix II device I/O pin provides an optional programmable pull-up resistor during user mode. If you enable this feature for an I/O pin, the pull-up resistor (typically 25 k Ω) weakly holds the output to the V_{CCIO} level of the output pin's bank.

Programmable pull-up resistors are only supported on user I/O pins, and are not supported on dedicated configuration pins, JTAG pins or dedicated clock pins.

Advanced I/O Standard Support

Stratix II device IOEs support the following I/O standards:

- 3.3-V LVTTL/LVCMOS
- 2.5-V LVTTL/LVCMOS
- 1.8-V LVTTL/LVCMOS
- 1.5-V LVCMOS
- 3.3-V PCI
- 3.3-V PCI-X mode 1
- LVDS
- LVPECL (on input and output clocks only)
- HyperTransport technology
- Differential 1.5-V HSTL Class I and II
- Differential 1.8-V HSTL Class I and II
- Differential SSTL-18 Class I and II
- Differential SSTL-2 Class I and II



For more information on JTAG, see the following documents:

- The *IEEE Std. 1149.1 (JTAG) Boundary-Scan Testing for Stratix II & Stratix II GX Devices* chapter of the *Stratix II Device Handbook, Volume 2* or the *Stratix II GX Device Handbook, Volume 2*
- Jam Programming & Test Language Specification

SignalTap II Embedded Logic Analyzer

Stratix II devices feature the SignalTap II embedded logic analyzer, which monitors design operation over a period of time through the IEEE Std. 1149.1 (JTAG) circuitry. You can analyze internal logic at speed without bringing internal signals to the I/O pins. This feature is particularly important for advanced packages, such as FineLine BGA® packages, because it can be difficult to add a connection to a pin during the debugging process after a board is designed and manufactured.

Configuration

The logic, circuitry, and interconnects in the Stratix II architecture are configured with CMOS SRAM elements. Altera® FPGA devices are reconfigurable and every device is tested with a high coverage production test program so you do not have to perform fault testing and can instead focus on simulation and design verification.

Stratix II devices are configured at system power-up with data stored in an Altera configuration device or provided by an external controller (e.g., a MAX® II device or microprocessor). Stratix II devices can be configured using the fast passive parallel (FPP), active serial (AS), passive serial (PS), passive parallel asynchronous (PPA), and JTAG configuration schemes. The Stratix II device's optimized interface allows microprocessors to configure it serially or in parallel, and synchronously or asynchronously. The interface also enables microprocessors to treat Stratix II devices as memory and configure them by writing to a virtual memory location, making reconfiguration easy.

In addition to the number of configuration methods supported, Stratix II devices also offer the design security, decompression, and remote system upgrade features. The design security feature, using configuration bitstream encryption and AES technology, provides a mechanism to protect your designs. The decompression feature allows Stratix II FPGAs to receive a compressed configuration bitstream and decompress this data in real-time, reducing storage requirements and configuration time. The remote system upgrade feature allows real-time system upgrades from remote locations of your Stratix II designs. For more information, see [“Configuration Schemes” on page 3–7](#).

you need to support configuration input voltages of 1.8 V/1.5 V, you should set the VCCSEL to a logic high and the V_{CCIO} of the bank that contains the configuration inputs to 1.8 V/1.5 V.



For more information on multi-volt support, including information on using TDO and nCEO in multi-volt systems, refer to the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Configuration Schemes

You can load the configuration data for a Stratix II device with one of five configuration schemes (see Table 3–5), chosen on the basis of the target application. You can use a configuration device, intelligent controller, or the JTAG port to configure a Stratix II device. A configuration device can automatically configure a Stratix II device at system power-up.

You can configure multiple Stratix II devices in any of the five configuration schemes by connecting the configuration enable (nCE) and configuration enable output (nCEO) pins on each device.

Stratix II FPGAs offer the following:

- Configuration data decompression to reduce configuration file storage
- Design security using configuration data encryption to protect your designs
- Remote system upgrades for remotely updating your Stratix II designs

Table 3–5 summarizes which configuration features can be used in each configuration scheme.

Table 3–5. Stratix II Configuration Features (Part 1 of 2)

Configuration Scheme	Configuration Method	Design Security	Decompression	Remote System Upgrade
FPP	MAX II device or microprocessor and flash device	✓ (1)	✓ (1)	✓
	Enhanced configuration device		✓ (2)	✓
AS	Serial configuration device	✓	✓	✓ (3)
PS	MAX II device or microprocessor and flash device	✓	✓	✓
	Enhanced configuration device	✓	✓	✓
	Download cable (4)	✓	✓	

Table 5–27. 1.8-V HSTL Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.71	1.80	1.89	V
V_{REF}	Input reference voltage		0.85	0.90	0.95	V
V_{TT}	Termination voltage		0.85	0.90	0.95	V
V_{IH} (DC)	DC high-level input voltage		$V_{REF} + 0.1$			V
V_{IL} (DC)	DC low-level input voltage		–0.3		$V_{REF} - 0.1$	V
V_{IH} (AC)	AC high-level input voltage		$V_{REF} + 0.2$			V
V_{IL} (AC)	AC low-level input voltage				$V_{REF} - 0.2$	V
V_{OH}	High-level output voltage	$I_{OH} = 16 \text{ mA}$ (1)	$V_{CCIO} - 0.4$			V
V_{OL}	Low-level output voltage	$I_{OH} = -16 \text{ mA}$ (1)			0.4	V

Note to Table 5–27:

- (1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–28. 1.8-V HSTL Class I & II Differential Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	I/O supply voltage		1.71	1.80	1.89	V
V_{DIF} (DC)	DC input differential voltage		0.2		$V_{CCIO} + 0.6 \text{ V}$	V
V_{CM} (DC)	DC common mode input voltage		0.78		1.12	V
V_{DIF} (AC)	AC differential input voltage		0.4		$V_{CCIO} + 0.6 \text{ V}$	V
V_{OX} (AC)	AC differential cross point voltage		0.68		0.90	V

Table 5–31. Series & Differential On-Chip Termination Specification for Left & Right I/O Banks

Symbol	Description	Conditions	Resistance Tolerance		
			Commercial Max	Industrial Max	Unit
25-Ω R_S 3.3/2.5	Internal series termination without calibration (25-Ω setting)	$V_{CCIO} = 3.3/2.5$ V	±30	±30	%
50-Ω R_S 3.3/2.5/1.8	Internal series termination without calibration (50-Ω setting)	$V_{CCIO} = 3.3/2.5/1.8$ V	±30	±30	%
50-Ω R_S 1.5	Internal series termination without calibration (50-Ω setting)	$V_{CCIO} = 1.5$ V	±36	±36	%
R_D	Internal differential termination for LVDS or HyperTransport technology (100-Ω setting)	$V_{CCIO} = 2.5$ V	±20	±25	%

Pin Capacitance

Table 5–32 shows the Stratix II device family pin capacitance.

Table 5–32. Stratix II Device Capacitance *Note (1)*

Symbol	Parameter	Typical	Unit
C_{IOTB}	Input capacitance on I/O pins in I/O banks 3, 4, 7, and 8.	5.0	pF
C_{IOLR}	Input capacitance on I/O pins in I/O banks 1, 2, 5, and 6, including high-speed differential receiver and transmitter pins.	6.1	pF
C_{CLKTB}	Input capacitance on top/bottom clock input pins: CLK[4..7] and CLK[12..15].	6.0	pF
C_{CLKLR}	Input capacitance on left/right clock inputs: CLK0, CLK2, CLK8, CLK10.	6.1	pF
C_{CLKLR+}	Input capacitance on left/right clock inputs: CLK1, CLK3, CLK9, and CLK11.	3.3	pF
C_{OUTFB}	Input capacitance on dual-purpose clock output/feedback pins in PLL banks 9, 10, 11, and 12.	6.7	pF

Note to Table 5–32:

- (1) Capacitance is sample-tested only. Capacitance is measured using time-domain reflections (TDR). Measurement accuracy is within ±0.5pF

Table 5–36. Stratix II Performance Notes (Part 3 of 6) *Note (1)*

Applications		Resources Used			Performance				
		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
DSP block	9 × 9-bit multiplier (5)	0	0	1	430.29	409.16	373.13	320.10	MHz
	18 × 18-bit multiplier (5)	0	0	1	410.17	390.01	356.12	305.06	MHz
	18 × 18-bit multiplier (7)	0	0	1	450.04	428.08	391.23	335.12	MHz
	36 × 36-bit multiplier (5)	0	0	1	250.00	238.15	217.48	186.60	MHz
	36 × 36-bit multiplier (6)	0	0	1	410.17	390.01	356.12	305.06	MHz
	18-bit, four-tap FIR filter	0	0	1	410.17	390.01	356.12	305.06	MHz
Larger designs	8-bit, 16-tap parallel FIR filter	58	0	4	259.06	240.61	217.15	185.01	MHz
	8-bit, 1024-point, streaming, three multipliers and five adders FFT function	2976	22	9	398.72	364.03	355.23	306.37	MHz
	8-bit, 1024-point, streaming, four multipliers and two adders FFT function	2781	22	12	398.56	409.16	347.22	311.13	MHz
	8-bit, 1024-point, single output, one parallel FFT engine, burst, three multipliers and five adders FFT function	984	5	3	425.17	365.76	346.98	292.39	MHz
	8-bit, 1024-point, single output, one parallel FFT engine, burst, four multipliers and two adders FFT function	919	5	4	427.53	378.78	357.14	307.59	MHz

Table 5–36. Stratix II Performance Notes (Part 4 of 6) *Note (1)*

Applications		Resources Used			Performance				
		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
Larger designs	8-bit, 1024-point, single output, two parallel FFT engines, burst, three multiplier and five adders FFT function	1725	10	6	430.29	401.92	373.13	319.08	MHz
	8-bit, 1024-point, single output, two parallel FFT engines, burst, four multipliers and two adders FFT function	1594	10	8	422.65	407.33	373.13	329.10	MHz
	8-bit, 1024-point, quadrant output, one parallel FFT engine, burst, three multipliers and five adders FFT function	2361	10	9	315.45	342.81	325.73	284.25	MHz
	8-bit, 1024-point, quadrant output, one parallel FFT engine, burst, four multipliers and two adders FFT function	2165	10	12	373.13	369.54	317.96	256.14	MHz
	8-bit, 1024-point, quadrant output, two parallel FFT engines, burst, three multipliers and five adders FFT function	3996	14	18	378.50	367.10	332.33	288.68	MHz
	8-bit, 1024-point, quadrant output, two parallel FFT engines, burst, four multipliers and two adders FFT function	3604	14	24	391.38	361.14	340.25	280.89	MHz

Internal Timing Parameters

See [Tables 5–37](#) through [5–42](#) for internal timing parameters.

Table 5–37. LE_FF Internal Timing Microparameters

Symbol	Parameter	-3 Speed Grade (1)		-3 Speed Grade (2)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (3)	Max	Min (3)	Max	Min (4)	Max	Min (3)	Max	
t _{SU}	LE register setup time before clock	90		95		104 104		121		ps
t _H	LE register hold time after clock	149		157		172 172		200		ps
t _{CO}	LE register clock-to-output delay	62	94	62	99	59 62	109	62	127	ps
t _{CLR}	Minimum clear pulse width	204		214		234 234		273		ps
t _{PRE}	Minimum preset pulse width	204		214		234 234		273		ps
t _{CLKL}	Minimum clock low time	612		642		703 703		820		ps
t _{CLKH}	Minimum clock high time	612		642		703 703		820		ps
t _{LUT}		162	378	162	397	162 170	435	162	507	ps
t _{ADDER}		354	619	354	650	354 372	712	354	829	ps

Notes to Table 5–37:

- (1) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (2) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
- (3) For the -3 and -5 speed grades, the minimum timing is for the commercial temperature grade. Only -4 speed grade devices offer the industrial temperature grade.
- (4) For the -4 speed grade, the first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.

Table 5–40. M512 Block Internal Timing Microparameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
$t_{M512DATAO1}$	Clock-to-output delay when using output registers	298	478	298	501	284 298	548	298	640	ps
$t_{M512DATAO2}$	Clock-to-output delay without output registers	2,102	2,345	2,102	2,461	2,003 2,102	2,695	2,102	3,141	ps
$t_{M512CLKL}$	Minimum clock low time	1,315		1,380		1,512 1,512		1,762		ps
$t_{M512CLKH}$	Minimum clock high time	1,315		1,380		1,512 1,512		1,762		ps
$t_{M512CLR}$	Minimum clear pulse width	144		151		165 165		192		ps

Notes to Table 5–40:

- (1) F_{MAX} of M512 block obtained using the Quartus II software does not necessarily equal to $1/T_{M512RC}$.
- (2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
- (4) For the -3 and -5 speed grades, the minimum timing is for the commercial temperature grade. Only -4 speed grade devices offer the industrial temperature grade.
- (5) For the -4 speed grade, the first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.

Table 5–41. M4K Block Internal Timing Microparameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
t_{M4KRC}	Synchronous read cycle time	1,462	2,240	1,462	2,351	1,393 1,462	2,575	1,462	3,000	ps
$t_{M4KWRESU}$	Write or read enable setup time before clock	22		23		25 25		29		ps
$t_{M4KWEREH}$	Write or read enable hold time after clock	203		213		233 233		272		ps
$t_{M4KBESU}$	Byte enable setup time before clock	22		23		25 25		29		ps
t_{M4KBEH}	Byte enable hold time after clock	203		213		233 233		272		ps

Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 2 of 8)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade (3)	-3 Speed Grade (4)	-4 Speed Grade	-5 Speed Grade	Unit
			Industrial	Commercial					
LVCMOS	4 mA	t _{OP}	1041	1091	2036	2136	2340	2448	ps
		t _{DIP}	1061	1113	2102	2206	2416	2538	ps
	8 mA	t _{OP}	952	999	1786	1874	2053	2153	ps
		t _{DIP}	972	1021	1852	1944	2129	2243	ps
	12 mA	t _{OP}	926	971	1720	1805	1977	2075	ps
		t _{DIP}	946	993	1786	1875	2053	2165	ps
	16 mA	t _{OP}	933	978	1693	1776	1946	2043	ps
		t _{DIP}	953	1000	1759	1846	2022	2133	ps
	20 mA	t _{OP}	921	965	1677	1759	1927	2025	ps
		t _{DIP}	941	987	1743	1829	2003	2115	ps
	24 mA (1)	t _{OP}	909	954	1659	1741	1906	2003	ps
		t _{DIP}	929	976	1725	1811	1982	2093	ps
2.5 V	4 mA	t _{OP}	1004	1053	2063	2165	2371	2480	ps
		t _{DIP}	1024	1075	2129	2235	2447	2570	ps
	8 mA	t _{OP}	955	1001	1841	1932	2116	2218	ps
		t _{DIP}	975	1023	1907	2002	2192	2308	ps
	12 mA	t _{OP}	934	980	1742	1828	2002	2101	ps
		t _{DIP}	954	1002	1808	1898	2078	2191	ps
	16 mA (1)	t _{OP}	918	962	1679	1762	1929	2027	ps
		t _{DIP}	938	984	1745	1832	2005	2117	ps

Table 5–79. Maximum Output Clock Toggle Rate Derating Factors (Part 2 of 5)

I/O Standard	Drive Strength	Maximum Output Clock Toggle Rate Derating Factors (ps/pF)								
		Column I/O Pins			Row I/O Pins			Dedicated Clock Outputs		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
1.8-V LVTTTL/LVCMOS	2 mA	951	1421	1421	951	1421	1421	904	1421	1421
	4 mA	405	516	516	405	516	516	393	516	516
	6 mA	261	325	325	261	325	325	253	325	325
	8 mA	223	274	274	223	274	274	224	274	274
	10 mA	194	236	236	-	-	-	199	236	236
	12 mA	174	209	209	-	-	-	180	209	209
1.5-V LVTTTL/LVCMOS	2 mA	652	963	963	652	963	963	618	963	963
	4 mA	333	347	347	333	347	347	270	347	347
	6 mA	182	247	247	-	-	-	198	247	247
	8 mA	135	194	194	-	-	-	155	194	194
SSTL-2 Class I	8 mA	364	680	680	364	680	680	350	680	680
	12 mA	163	207	207	163	207	207	188	207	207
SSTL-2 Class II	16 mA	118	147	147	118	147	147	94	147	147
	20 mA	99	122	122	-	-	-	87	122	122
	24 mA	91	116	116	-	-	-	85	116	116
SSTL-18 Class I	4 mA	458	570	570	458	570	570	505	570	570
	6 mA	305	380	380	305	380	380	336	380	380
	8 mA	225	282	282	225	282	282	248	282	282
	10 mA	167	220	220	167	220	220	190	220	220
	12 mA	129	175	175	-	-	-	148	175	175
SSTL-18 Class II	8 mA	173	206	206	-	-	-	155	206	206
	16 mA	150	160	160	-	-	-	140	160	160
	18 mA	120	130	130	-	-	-	110	130	130
	20 mA	109	127	127	-	-	-	94	127	127
SSTL-2 Class I	8 mA	364	680	680	364	680	680	350	680	680
	12 mA	163	207	207	163	207	207	188	207	207
SSTL-2 Class II	16 mA	118	147	147	118	147	147	94	147	147
	20 mA	99	122	122	-	-	-	87	122	122
	24 mA	91	116	116	-	-	-	85	116	116